

A National Science Foundation Science & Technology Center Ultrafast Electrical Pulse Generation Justin in Photoconductive Switches

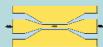
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Abstract

Ultra-fast photoconductive switches (PCS) can be used to generate very fast electrical pulses. These pulses can be used to further examine the dynamics of magnetic switching. The project goal was to design and experimentally measure a photoconductive switch that exhibits sub picosecond electrical pulses and that can deliver a large current density to a load.

Simulation



AWP's Microwave Office

 Short voltage pulse was sent down the modeled transmission line

- Varied parameters
- Observed at
 multiple locations

Barmonic Balance: Current vs Time

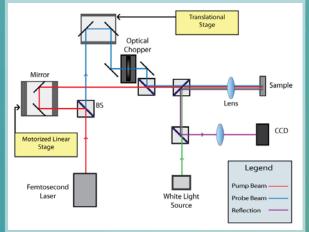
Time (ne)

0.02

0.01

Transmission line modeled with

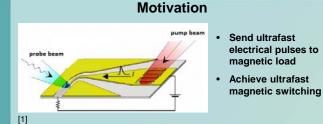
Optical Setup



References

[1] Modified picture from "Research – Lawrence Berkeley National Laboratory", http://xraysweb.lbl.gov/peem2/webpage/Research.shtml

[2] http://www.batop.com/information/pictures/PCA_band_diagramme.png



active area

3

Gap to Width Ratio = 0.6

match

50 Ohms impedance

Design

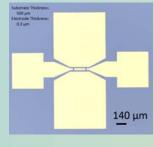
W

60 µm

Center for Energy Efficient Electronics Science

GaAs subtrate

- Gold electrodes
- Coplanar waveguide transmission line
- Active area utilized the multiple finger structure

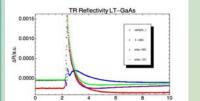


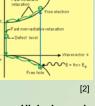
Discussion

- Project followed a three step process: simulating, fabricating, and experimental testing
- The R_on (resistance across the active area) impedance and the tapered region length were found to have minor effects on current density
- Simulations revealed high current density is possible with almost no broadening
- Currently unable to experimentally characterize the electrical signal in the device
 - Signal showed no peak point as path delays were varied
- First device showed a resistance lower than expected
- Saturation of carriers has not been reached
- Further testing is necessary

Low Temperature – GaAs (LT-GaAs)

- Has desired properties for PCS
- Defects in the band gap lead to fast non-radiative recombination
- Time interval < 1 ps



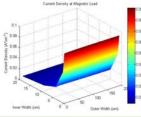


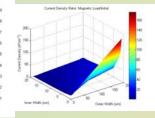
High change in reflectivity shows generation of electron-hole pairs

Results

- Simulation results were found as expected
- Large outer transmission line width and small inner transmission line width can provide the desired result, a high current density







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